Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
09/727,491	CHEN ET AL.
Examiner	Art Unit
Cong-Lac Huynh	2178

SEARCHED				
Class	Subclass	Date	Examiner	
715	500.1	5/25/2006	CLH	
	723	5/25/2006	CLH	
	501.1	5/25/2006	CLH	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East	5/25/2006	CLH		
ACM	5/25/2006	CLH		
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